

Search Notes**Application/Control No.**

10/529,145

Examiner

/Yonel Beaulieu/

Applicant(s)/Patent under Reexamination

OHNISHI ET AL.

Art Unit

3661

SEARCHED

Class	Subclass	Date	Examiner
70	200	1/11/2008	YB
	117-119		
	213-215		
342	357.06		
	357.12		
340	988		

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
WEST	1/11/2008	YB

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner